

Search Notes



Application/Control No.

10/784,260

Examiner

Hiep T. Nguyen

Applicant(s)/Patent under Reexamination

FUJIBAYASHI, AKIRA

Art Unit

2187

SEARCHED

Class	Subclass	Date	Examiner
711	170	Text search only - see EAST search print out.	
	162		
	113		
	117		
710	56	11/26/05 HTP	
	57		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
PG - PUB		Text search. 11/26/05 HTP	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST search list is attached.	11/26/05 HTP	
NPL search using terms similar to EAST search.		
Inventorship search.		